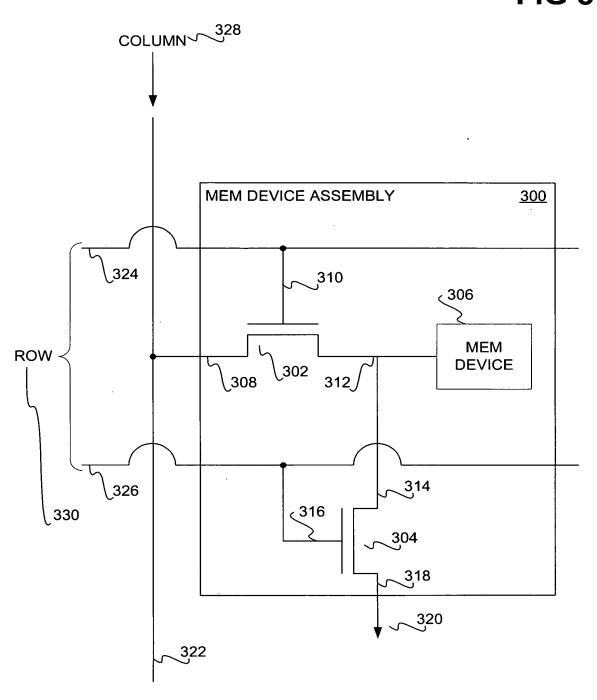
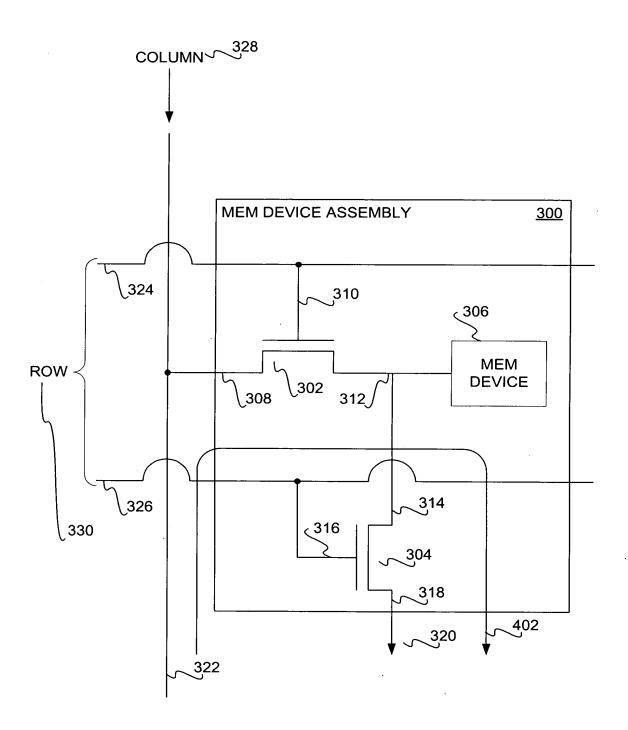


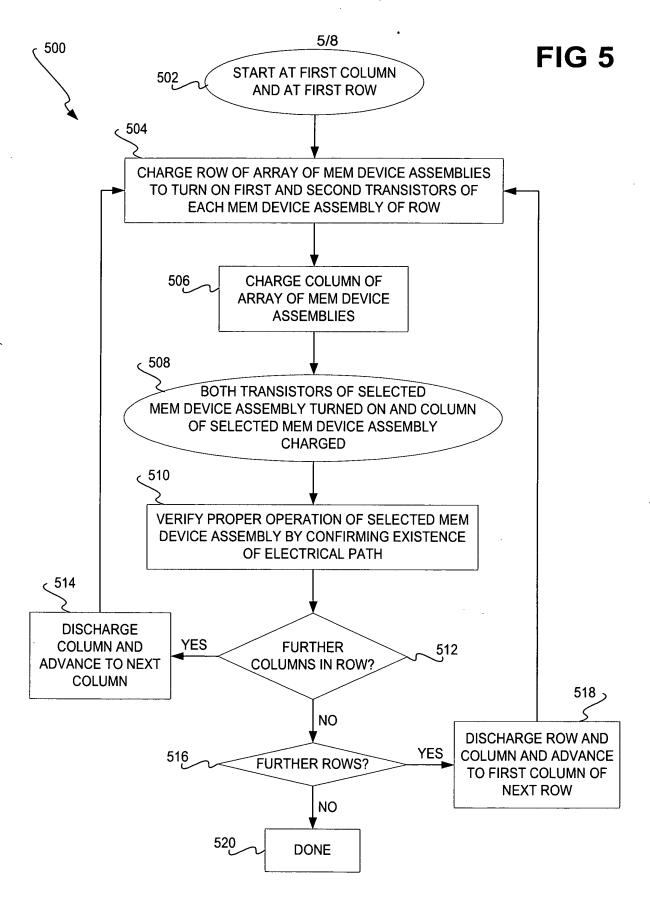
FIG 3



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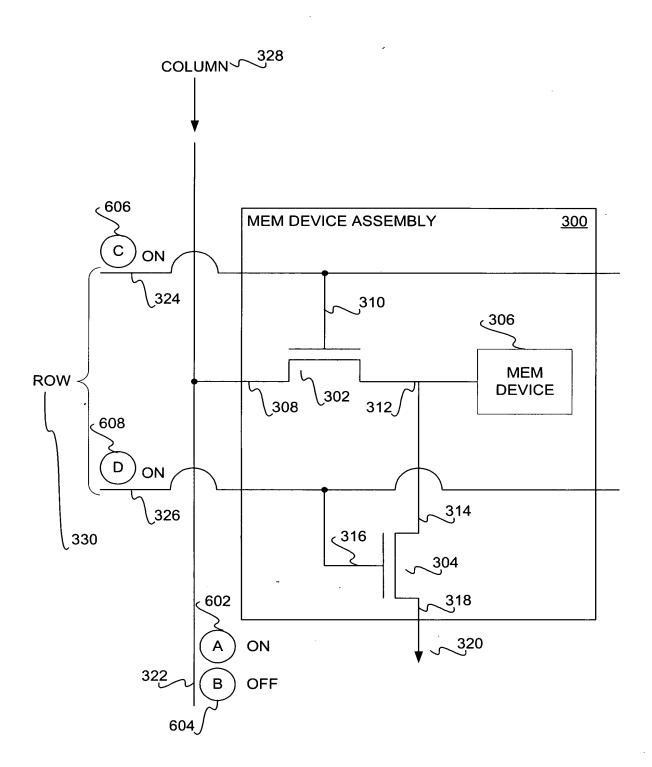
FIG 4

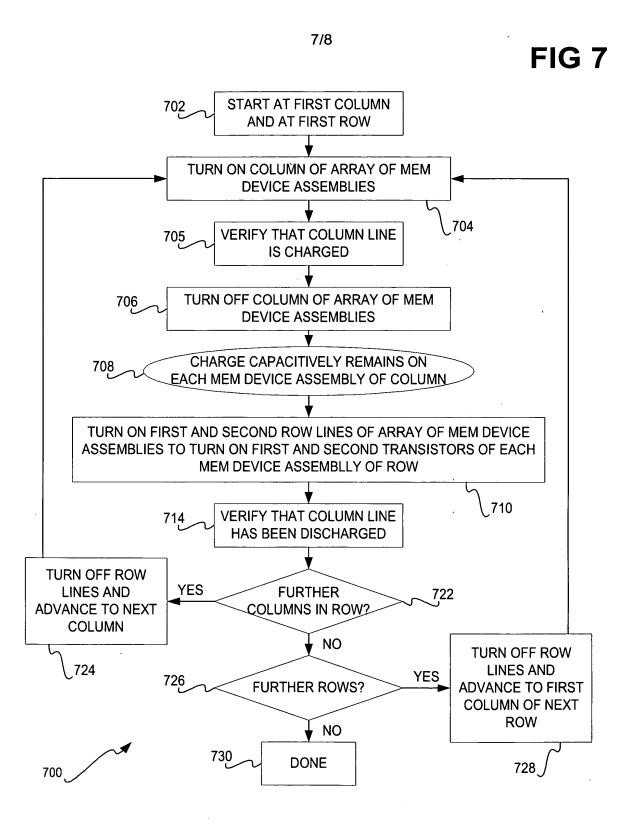




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FIG 6





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FIG 8

PROVIDE, FOR EACH NODE OF AN ARRAY OF NODES, A MEM DEVICE, A FIRST TRANSISTOR, AND A SECOND TRANSISTOR

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SITUATE A TESTING MECHANISM OUTSIDE OF THE ARRAY OF NODES THAT IS CAPABLE OF TESTING EACH NODE FOR PROPER OPERATION WITHOUT DIRECTLY ELECTRICALLY READING THE MEM DEVICE OF EACH NODE

